

### $2^{nd}$ generation thinQ!<sup>TM</sup> SiC Schottky Diode

#### Features:

#### **Applications:**

SMPS, PFC, snubber

- Revolutionary Semiconductor Material -Silicon Carbide
- Switching Behaviour Benchmark
- No Reverse Recovery / No Forward Recovery
- Temperature Independent Switching Behaviour
- Qualified According to JEDEC<sup>1)</sup> Based on **Target Applications**

Chip Type	$V_{R}$	<i>I</i> <sub>Fn</sub>	Die Size	Package			
IDC05S60CE	600V	5A	1.45 x 1.162 mm <sup>2</sup>	sawn on foil			
Mechanical Parameter	'S						
Die size			1.4	5x 1.162			
Area total				1.68			
Anode pad size			1.21	3 x 0.925			
Thickness				355	μm		
Wafer size		100		mm			
Max. possible chips per wafer			4051				
Passivation frontside				Photoimide			
Pad metal				3200 nm AlSiCu			
Backside metal			Ni Ag –system				
Die bond			Electrically conductive epoxy glue and soft solder				
Wire bond			AI, ≤500μm				
Reject ink dot size			Ø 0.65mm; max 1.2mm				
	for original and sealed MBB bags  Ambient atmosphere air, Temperature 17°C – 3  < 6 month				25°C,		
Storage environment <sup>1)</sup>	for one:	And to IECCO701 2 2. Atmosphere . 000/ Nitragen or inc					

Acc. to IEC60721-3-3: Atmosphere >99% Nitrogen or inert

gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month

Designed for climate condition under operation according to IEC60721-3-3, class 3K3

for open MBB

bags

<sup>1)</sup> Designed for storage conditions according to Infineon TR14 (Application Note "Storage of Products Supplied by Infineon Technologies)



#### **Maximum Ratings**

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	$V_{RRM}$	<i>T</i> <sub>vj</sub> =25 °C	600	V	
DC blocking voltage	V <sub>DC</sub>		600	]	
Continuous forward current, limited by $T_{vjmax}$	I <sub>F</sub>	T <sub>vj</sub> < 150°C	5		
Surge non repetitive forward current,	,	$T_{\rm C}$ =25°C, $t_{\rm P}$ =10 ms	42	1	
sine halfwave	$I_{F,SM}$	$T_{\rm C} = 150^{\circ} {\rm C}$ , $t_{\rm P} = 10 {\rm ms}$		Α	
Repetitive peak forward current, limited by thermal resistance $R_{th}$	I <sub>F,RM</sub>	$T_{\rm C} = 100^{\circ} {\rm C}, \ T_{\rm vj} = 150^{\circ} {\rm C}, \ D = 0.1$	21		
Non-repetitive peak forward current	I <sub>F,max</sub>	$T_{\rm C} = 25^{\circ} {\rm C}, \ t_{\rm P} = 10 {\rm \mu s}$	180		
i <sup>2</sup> t value	$\int i^2 dt$	$T_{\rm C}$ =25°C, $t_{\rm P}$ =10 ms	9	- A <sup>2</sup> s	
i i value	$\int_{0}^{T} dt$	$T_{\rm C} = 150^{\circ} {\rm C}$ , $t_{\rm P} = 10 {\rm ms}$		AS	
Operating junction and storage temperature range	$T_{\rm vj}$ , $T_{\rm stg}$		-55+175	°C	

### Static Characteristics (tested on wafer), $\mathcal{T}_{v_j}$ = 25 °C

Parameter	Symbol	Conditions	Value			Unit
Parameter			min.	Тур.	max.	Oiiil
Reverse current	I <sub>R</sub>	V <sub>R</sub> =600V		0.6	70	μΑ
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =5A		1.5	1.7	V

#### Static Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
raiailletei		Conditions	min.	Тур.	max.	Oilit
Reverse current	$I_{R}$	$V_{\rm R} = 600  \rm V$ , $T_{\rm vj} = 150  \rm ^{\circ}  \rm C$		2.5	700	μΑ
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =5A, T <sub>vj</sub> =150°C		1.7	2.1	V



#### **Dynamic Characteristics** (not subject to production test - verified by design / characterization)

Davamastan	Councile of	Conditions		Value			
Parameter	Symbol			min.	Тур.	max.	Unit
Total capacitive charge <sup>3)</sup>	Q <sub>C</sub>	$I_F <= I_{F,max}$	T <sub>vj</sub> =150°C		12		nC
Switching time <sup>2)</sup>	tc	$\frac{di/dt=200A/\mu s}{V_R=400V}$	T <sub>vj</sub> =150°C			<10	ns
			<i>V</i> <sub>R</sub> = 1 V		240		
Total capacitance	С	f=1MHz	V <sub>R</sub> =300V		30		pF
			V <sub>R</sub> =600V		30		

#### **Further Electrical Characteristics**

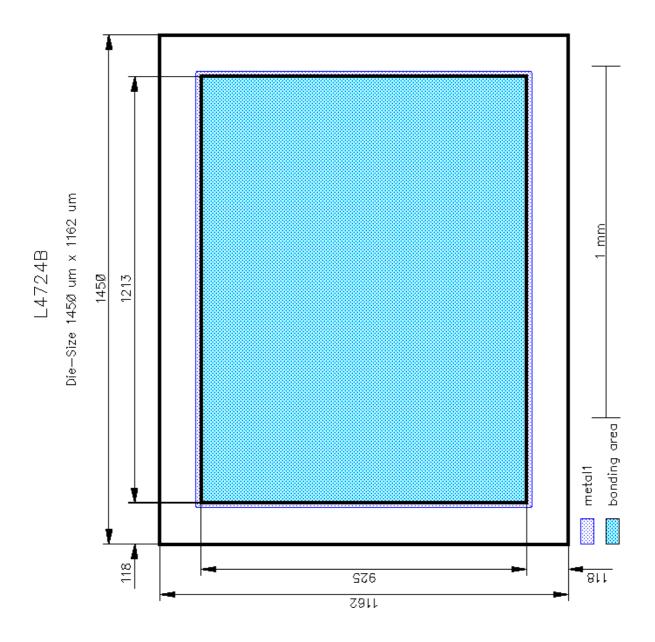
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet IDT05S60C	Rev. 2.1
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 $<sup>^{1)}</sup>$  J-STD20 and JESD22  $^{2)}$   $t_{\rm c}$  is the time constant for the capacitive displacement current waveform (independent from  $T_{\rm vj}{=}150\,^{\circ}{\rm C}$ ,  $I_{\rm LOAD}$  and dl/dt), different from  $t_{\rm rr}$ , which is dependent on  $T_{\rm vj}$  =150°C,  $I_{\rm LOAD}$ , dl/dt. No reverse recovery time constant  $t_{\rm rr}$  due to absence of minority carrier inject.  $^{3)}$  Only capacitive charge occurring, guaranteed by design (independent from  $T_{\rm vj}$ ,  $I_{\rm LOAD}$  and dl/dt).



#### **Chip Drawing**



### A: Anode pad



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date

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